

Application/Control No.	Applicant(s)/Patent under Reexamination
10/635,468	OSHIMA ET AL.
Examiner	Art Unit
Dac V Ha	2634

	SEARCHED				
Class	Subclass	Date	Examiner		
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	279,281				
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH (INCLUDING SEAR	NOTES CH STRATEG	Y)
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